# Abstracts

## 100 GHz On-Wafer S-Parameter Measurements by Electrooptic Sampling

*R. Majidi-Ahy, B.A. Auld and D.M. Bloom. "100 GHz On-Wafer S-Parameter Measurements by Electrooptic Sampling." 1989 MTT-S International Microwave Symposium Digest 89.1 (1989 Vol. I [MWSYM]): 299-302.*

We describe the electrooptic sampling system at Stanford configured for millimeter-wave measurements. An active wafer probe frequency-multiplier, developed for supplying the stimulus signal for these measurements is also described. 100 GHz on-wafer S-parameter measurements of linear circuits, time waveforms of nonlinear circuits and propagation characteristics of uniplanar waveguides on GaAs are discussed.

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